

L Number	Hits	Search Text	DB	Time stamp
1	11504	250/306 or 250/307 or 250/310 or 250/311 or 250/442.11 or 250/397 or 250/396r	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM TDB	2004/06/17 16:45
2	514937	@pd>=20040213	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM TDB	2004/06/17 16:45
3	337	@ad>=20040213	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM TDB	2004/06/17 16:45
4	50	((electron adj microscope) or SEM or TEM) AND ((stereovision or stereoscopic or stereo-meter or parallax or stereoimage or stereo-image or (stereo near3 image\$3)) or ((three NEAR2 demension\$3) or three-demension\$3 or 3D or 3-D)) And ((beam or ebeam or e-beam) near2 (tilt\$5 or ang\$5) near2 (specimen or sample or object))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM TDB	2004/06/17 16:50
5	50	((electron adj microscope) or SEM or TEM) AND ((stereovision or stereoscopic or stereo-meter or parallax or stereoimage or stereo-image or (stereo near3 image\$3)) or ((three NEAR2 demension\$3) or three-demension\$3 or 3D or 3-D)) And ((beam or ebeam or e-beam) near2 (tilt\$5 or ang\$5) near2 (specimen or sample or object)) And (((electron adj beam) or ebeam or e-beam) WITH (specimen or sample or object))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM TDB	2004/06/17 16:50
6	32	(Measur\$6 WITH template) and (((((electron adj microscope) or SEM or TEM) AND ((stereovision or stereoscopic or stereo-meter or parallax or stereoimage or stereo-image or (stereo near3 image\$3)) or ((three NEAR2 demension\$3) or three-demension\$3 or 3D or 3-D)))) (Rectifying or correcting) WITH (parameters or measurement)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM TDB	2004/06/17 16:51
7	14550	(Rectifying or correcting) WITH (parameters or measurement)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM TDB	2004/06/17 16:54
8	526120	(250/306 or 250/307 or 250/310 or 250/311 or 250/442.11 or 250/397 or 250/396r) or @pd>=20040213	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM TDB	2004/06/17 16:51
9	121	((Rectifying or correcting) WITH (parameters or measurement)) and (250/306 or 250/307 or 250/310 or 250/311 or 250/442.11 or 250/397 or 250/396r)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM TDB	2004/06/17 16:51
10	6944	(Rectifying or correcting) NEAR4 (parameters or measurement)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM TDB	2004/06/17 16:54
11	55	((Rectifying or correcting) NEAR4 (parameters or measurement)) and (250/306 or 250/307 or 250/310 or 250/311 or 250/442.11 or 250/397 or 250/396r)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM TDB	2004/06/17 16:54

12	4319	((Rectifying or correcting) NEAR2 (parameters or measurement))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM TDB	2004/06/17 16:54
13	39	((Rectifying or correcting) NEAR2 (parameters or measurement)) and (250/306 or 250/307 or 250/310 or 250/311 or 250/442.11 or 250/397 or 250/396r)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM TDB	2004/06/17 16:57
14	60042	((sample or specimen or substrate or relative or angle) NEAR2 tilt\$3)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM TDB	2004/06/17 16:57
15	561	((((sample or specimen or substrate or relative or angle) NEAR2 tilt\$3)) and (250/306 or 250/307 or 250/310 or 250/311 or 250/442.11 or 250/397 or 250/396r))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM TDB	2004/06/17 16:57
16	3	(((((sample or specimen or substrate or relative or angle) NEAR2 tilt\$3)) and (250/306 or 250/307 or 250/310 or 250/311 or 250/442.11 or 250/397 or 250/396r)) and (((Rectifying or correcting) NEAR2 (parameters or measurement)) and (250/306 or 250/307 or 250/310 or 250/311 or 250/442.11 or 250/397 or 250/396r))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM TDB	2004/06/17 16:57
17	5	(((((sample or specimen or substrate or relative or angle) NEAR2 tilt\$3)) and (250/306 or 250/307 or 250/310 or 250/311 or 250/442.11 or 250/397 or 250/396r)) and (((Rectifying or correcting) WITH (parameters or measurement)) and (250/306 or 250/307 or 250/310 or 250/311 or 250/442.11 or 250/397 or 250/396r))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM TDB	2004/06/17 16:58
19	168	((((electron adj microscope) or SEM or TEM) AND (stereovision or stereoscopic or stereo-meter or parallax or stereoimage or stereo-image or (stereo near3 image\$3)) or ((three NEAR2 demension\$3) or three-demension\$3 or 3D or 3-D)) And ((beam or ebeam or e-beam) near2 (tilt\$5 or ang\$5) near2 (specimen or sample or object))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM TDB	2004/06/17 17:23
18	5	(Measur\$6 SAME template SAME reference) and (((((electron adj microscope) or SEM or TEM) AND ((stereovision or stereoscopic or stereo-meter or parallax or stereoimage or stereo-image or (stereo near3 image\$3)) or ((three NEAR2 demension\$3) or three-demension\$3 or 3D or 3-D))))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM TDB	2004/06/17 17:23

20	81	((((electron adj microscope) or SEM or TEM) AND ((stereovision or stereoscopic or stereo-meter or parallax or stereoimage or stereo-image or (stereo near3 image\$3)) or ((three NEAR2 demension\$3) or three-demension\$3 or 3D or 3-D))) And ((beam or ebeam or e-beam) near2 (tilt\$5 or ang\$5) near2 (specimen or sample or object))) or (((electron adj microscope) or SEM or TEM) AND ((stereovision or stereoscopic or stereo-meter or parallax or stereoimage or stereo-image or (stereo near3 image\$3)) or ((three NEAR2 demension\$3) or three-demension\$3 or 3D or 3-D))) And ((beam or ebeam or e-beam) near2 (tilt\$5 or ang\$5) near2 (specimen or sample or object)) And (((electron adj beam) or ebeam or e-beam) WITH (specimen or sample or object)) or ((Measur\$6 WITH template) and (((electron adj microscope) or SEM or TEM) AND ((stereovision or stereoscopic or stereo-meter or parallax or stereoimage or stereo-image or (stereo near3 image\$3)) or ((three NEAR2 demension\$3) or three-demension\$3 or 3D or 3-D))))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/06/17 17:24
21	30	(((((electron adj microscope) or SEM or TEM) AND ((stereovision or stereoscopic or stereo-meter or parallax or stereoimage or stereo-image or (stereo near3 image\$3)) or ((three NEAR2 demension\$3) or three-demension\$3 or 3D or 3-D))) And ((beam or ebeam or e-beam) near2 (tilt\$5 or ang\$5) near2 (specimen or sample or object))) or (((electron adj microscope) or SEM or TEM) AND ((stereovision or stereoscopic or stereo-meter or parallax or stereoimage or stereo-image or (stereo near3 image\$3)) or ((three NEAR2 demension\$3) or three-demension\$3 or 3D or 3-D))) And ((beam or ebeam or e-beam) near2 (tilt\$5 or ang\$5) near2 (specimen or sample or object)) And (((electron adj beam) or ebeam or e-beam) WITH (specimen or sample or object)) or ((Measur\$6 WITH template) and (((electron adj microscope) or SEM or TEM) AND ((stereovision or stereoscopic or stereo-meter or parallax or stereoimage or stereo-image or (stereo near3 image\$3)) or ((three NEAR2 demension\$3) or three-demension\$3 or 3D or 3-D)))) And ((beam or ebeam or e-beam) near2 (tilt\$5 or ang\$5) near2 (specimen or sample or object)) And (((electron adj beam) or ebeam or e-beam) WITH (specimen or sample or object)) or ((Measur\$6 WITH template) and (((electron adj microscope) or SEM or TEM) AND ((stereovision or stereoscopic or stereo-meter or parallax or stereoimage or stereo-image or (stereo near3 image\$3)) or ((three NEAR2 demension\$3) or three-demension\$3 or 3D or 3-D)))) and ((250/306 or 250/307 or 250/310 or 250/311 or 250/442.11 or 250/397 or 250/396r) or @pd>=20040213))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/06/17 17:24
22	30	((((electron adj microscope) or SEM or TEM) AND (stereovision or stereoscopic or stereo-meter or parallax or stereoimage or stereo-image or (stereo near3 image\$3)) or ((three NEAR2 demension\$3) or three-demension\$3 or 3D or 3-D))) And ((beam or ebeam or e-beam) near2 (tilt\$5 or ang\$5) near2 (specimen or sample or object))) and ((250/306 or 250/307 or 250/310 or 250/311 or 250/442.11 or 250/397 or 250/396r) or @pd>=20040213))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/06/17 17:24

24	35	<p>(((((electron adj microscope) or SEM or TEM) AND (stereovision or stereoscopic or stereo-meter or parallax or stereoimage or stereo-image or (stereo near3 image\$3)) or ((three NEAR2 demension\$3) or three-demension\$3 or 3D or 3-D)) And ((beam or ebeam or e-beam) near2 (tilt\$5 or ang\$5) near2 (specimen or sample or object))) and ((250/306 or 250/307 or 250/310 or 250/311 or 250/442.11 or 250/397 or 250/396r) or @pd>=20040213)) or (((((electron adj microscope) or SEM or TEM) AND ((stereovision or stereoscopic or stereo-meter or parallax or stereoimage or stereo-image or (stereo near3 image\$3)) or ((three NEAR2 demension\$3) or three-demension\$3 or 3D or 3-D)) And ((beam or ebeam or e-beam) near2 (tilt\$5 or ang\$5) near2 (specimen or sample or object))) or (((electron adj microscope) or SEM or TEM) AND ((stereovision or stereoscopic or stereo-meter or parallax or stereoimage or (stereo near3 image\$3)) or ((three NEAR2 demension\$3) or three-demension\$3 or 3D or 3-D)) And ((beam or ebeam or e-beam) near2 (tilt\$5 or ang\$5) near2 (specimen or sample or object)) And (((electron adj beam) or ebeam or e-beam) WITH (specimen or sample or object))) or ((Measur\$6 WITH template) and (((electron adj microscope) or SEM or TEM) AND ((stereovision or stereoscopic or stereo-meter or parallax or stereoimage or stereo-image or (stereo near3 image\$3)) or ((three NEAR2 demension\$3) or three-demension\$3 or 3D or 3-D)))))) and ((250/306 or 250/307 or 250/310 or 250/311 or 250/442.11 or 250/397 or 250/396r) or @pd>=20040213))</p>	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/06/17 17:25
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